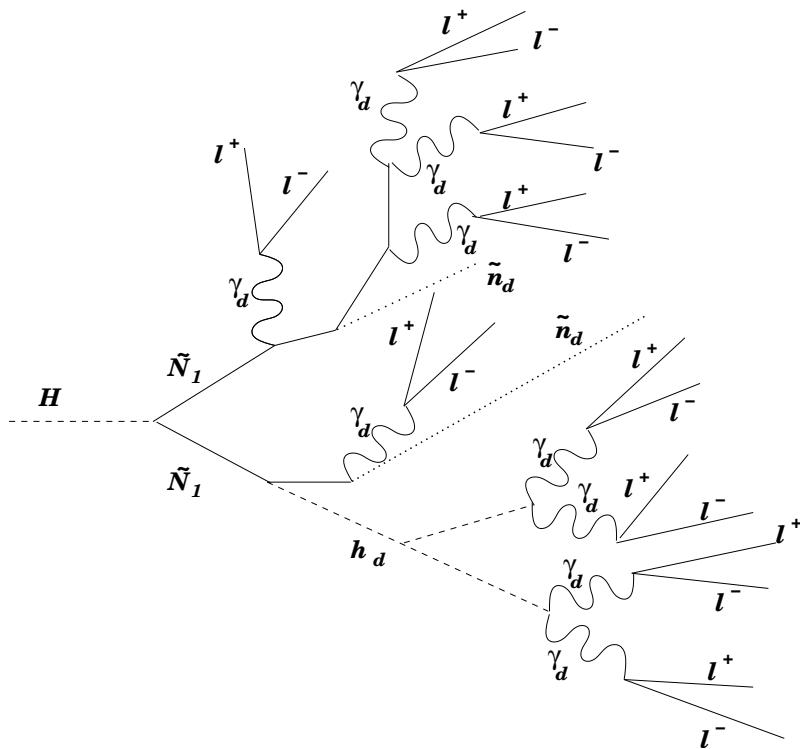


A Search for Low-Energy Leptons and Lepton Jets in W and Z Events at CDF



Scott Wilbur
University of Chicago
On behalf of the CDF Collaboration

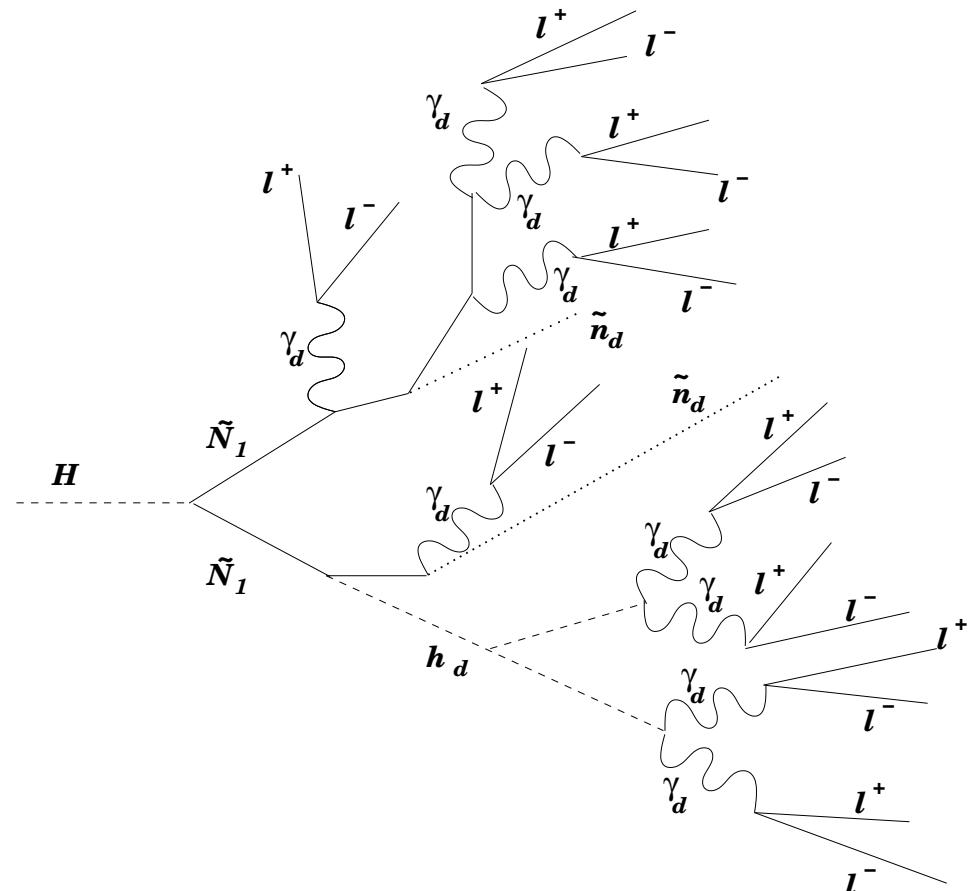
New Perspectives in Physics, Fermilab, May 31st

A Model-Independent Search

- Many models predict extra leptons and lepton jets
 - SUSY, Higgs decays through dark sector, dark matter models to explain leptonic cosmic ray excess
 - We don't want to optimize too heavily for one and ignore others
- We perform a very general signature-based search for events with extra leptons
- We choose a representative model to test: Neutralino Benchmark Model from A. Falkowski, J. T. Ruderman, T. Volansky and J. Zupan, arXiv:1002.2952 [hep-ph]
- We also present results in a model-independent way

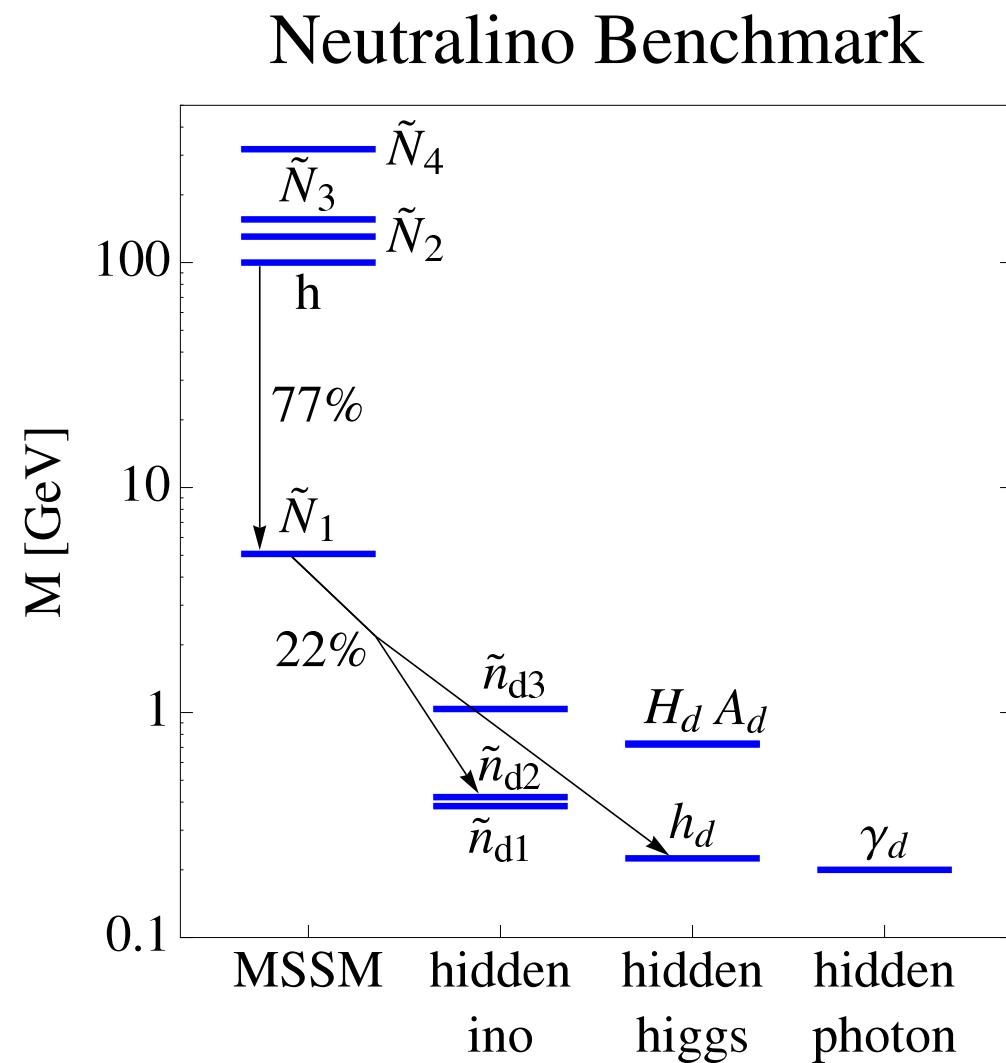
Overview of Signal

- Adaptation of Neutralino Benchmark Model
- Particular parameters from Matt Reece (Princeton) and Lian-Tao Wang (U. Chicago)
- Standard Model production of W or $Z + \text{Higgs}$
- Higgs decays through neutralinos and dark sector
- Model can also explain electron and positron cosmic ray excesses as DM annihilation
- As in many models, leptons are soft: could have evaded previous searches



Dark Sector Hidden Higgs Model

- SUSY Parameters: $\mu = 149$ GeV,
 $m_{\tilde{N}_1} = 13$ GeV, $m_{\tilde{N}_2} = 286$ GeV,
 $\tan(\beta) = 3.5$, $\sin(\alpha) = -0.28$
 - SUSY LSP: $m_{\chi_0} = 10$ GeV
- $m_H = 120$ GeV
- Dark Sector:
 - $m_{\chi_d} = 1$ GeV, $m_{\gamma_d} = 300$ MeV
 - $\gamma_d \rightarrow e^+ e^-$ (52.5%)
 - $\gamma_d \rightarrow \mu^+ \mu^-$ (46.6%)
 - $\gamma_d \rightarrow \pi^+ \pi^-$ (0.9%)
- Model the χ_0 decay to dark sector:
 - $\chi_0 \rightarrow \chi_d + 2\gamma_d$ (33%)
 - $\chi_0 \rightarrow \chi_d + 3\gamma_d$ (33%)
 - $\chi_0 \rightarrow \chi_d + 4\gamma_d$ (33%)

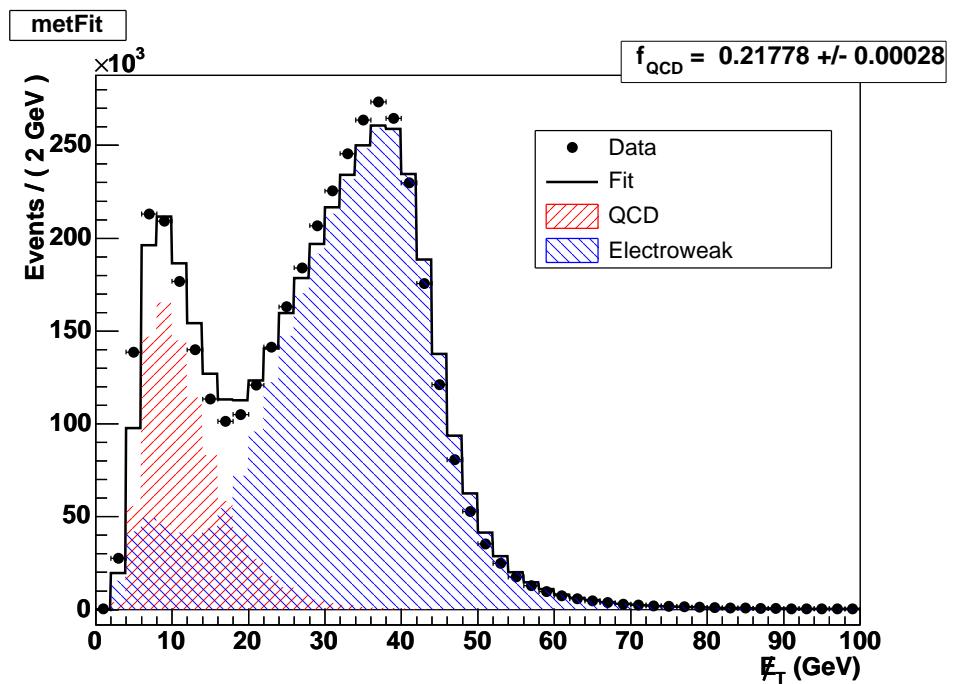


Analysis Strategy

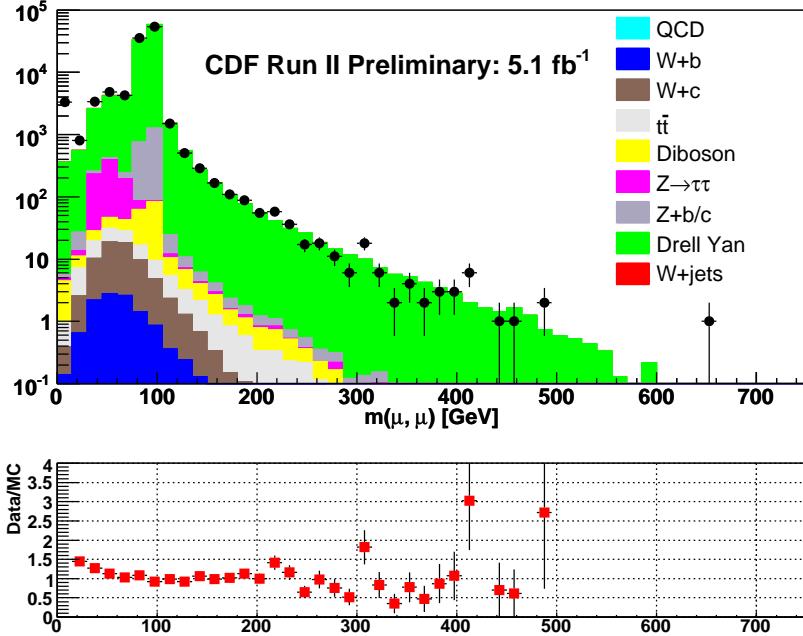
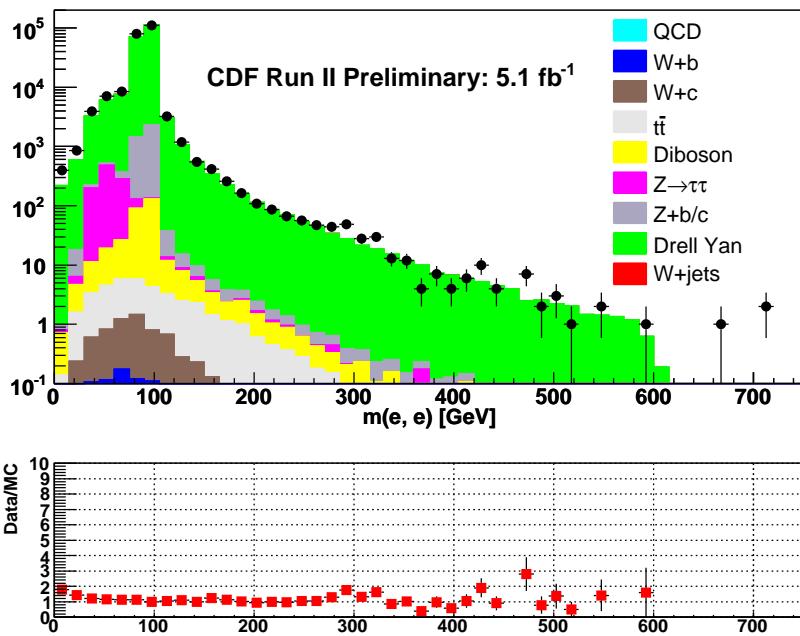
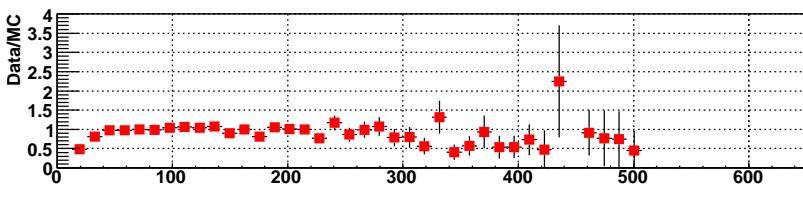
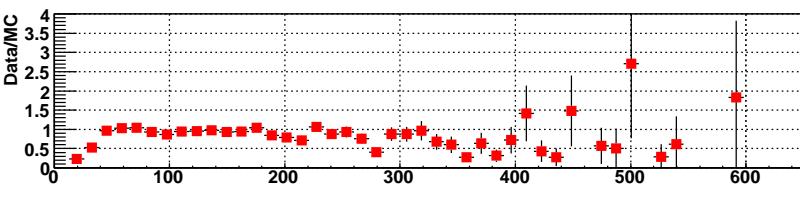
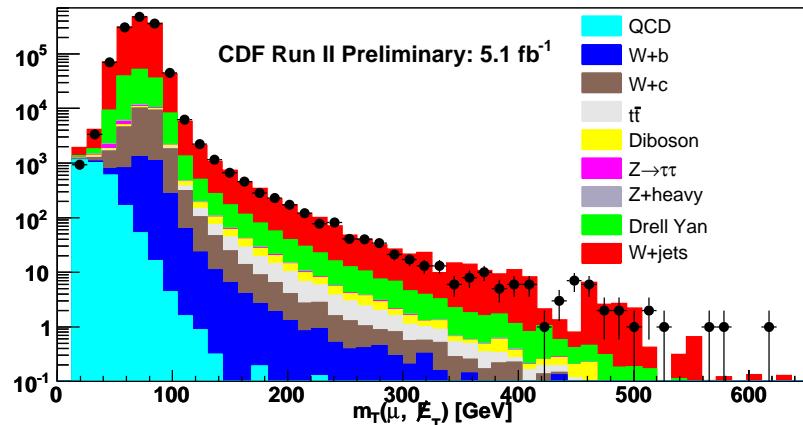
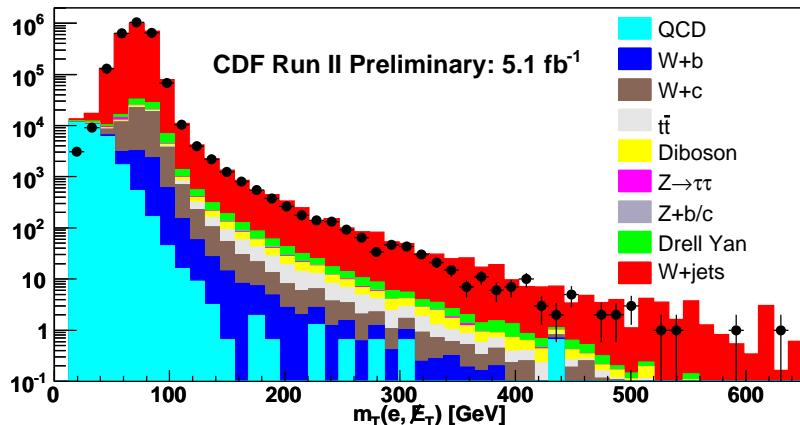
- We use 5.1 fb^{-1} of CDF data, collected from Dec. 2004 to Jan. 2010
- Trigger on leptonic W or Z with standard CDF high- p_T electron and muon cuts, validate W and Z
- Develop soft lepton identification - p_T down to 1 GeV for electrons, 3 GeV for muons
- Parameterize response of soft lepton ID to calculate expected additional leptons in SM
- Normalize predictions to $W/Z + \text{exactly one lepton}$ bin
- Count events with multiple additional leptons
- Set limit (or observe excess) based on the number of events with multiple additional electrons and muons

Background Estimation

- Use standard CDF MC samples to model EW processes
- Use data-driven technique to model QCD background
 - Electroweak E_T template from MC
 - QCD E_T template from anti-electron selection in data
 - Fit the E_T distribution to find the fraction of events from electroweak and QCD processes



Validation of High- p_T Sample

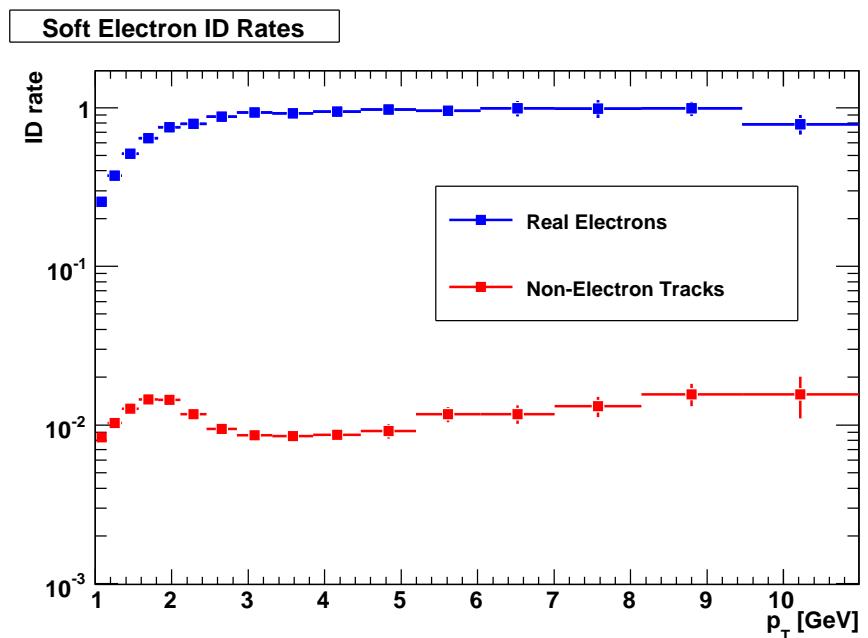


Soft Electrons

- Likelihood-based ID
 - Tracking chamber dE/dx - more useful at low p_T
 - Energy deposited in preradiator, EM and hadronic calorimeters
 - New algorithm for matching tracks to showermax clusters
- Formulated completely with data
 - Pure real sample from conversions
 - Pure fake sample from generic tracks (with conversions, heavy flavor, and hard electrons removed)
- $\mathcal{L} = \frac{\prod Q_i}{1 + \prod Q_i}$, where $Q_i = \frac{P(x_i|\text{real})}{P(x_i|\text{fake})}$

Soft Electron Efficiency and Fake Rate

- Pure real sample from conversions
- Pure fake sample from generic tracks (with conversions, heavy flavor, and hard electrons removed)
- Response measured in training samples and parameterized in p_T , η , isolation
- Calculated efficiency and fake rate is applied to the MC to predict SM background
- Systematic uncertainty calculated from difference between muon- and jet- triggered fake samples

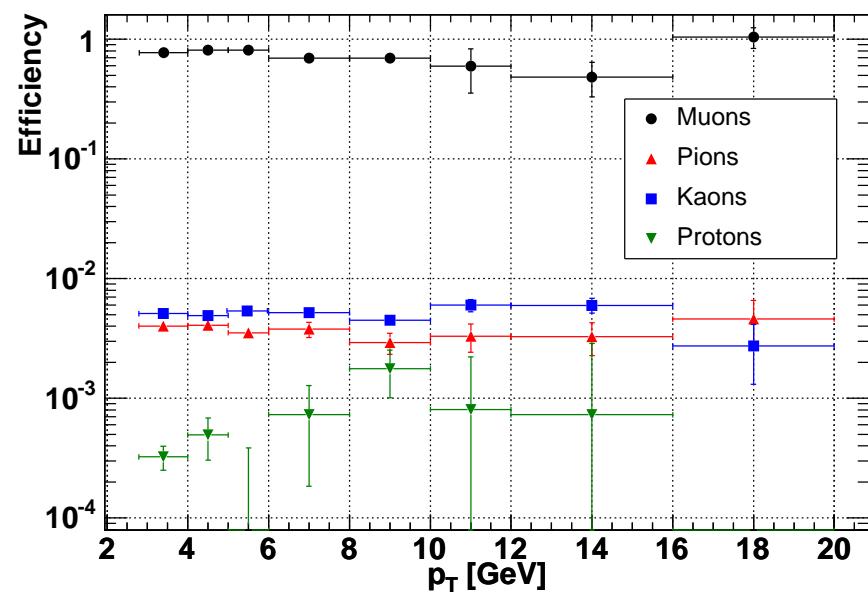


Soft Muons

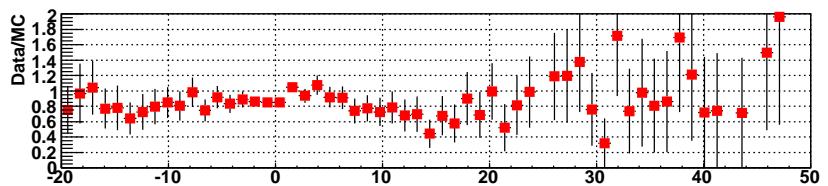
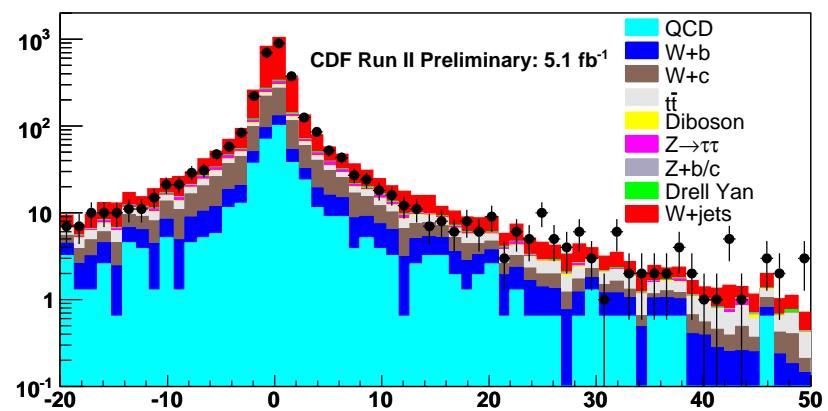
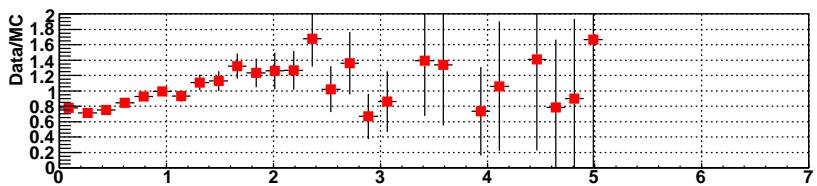
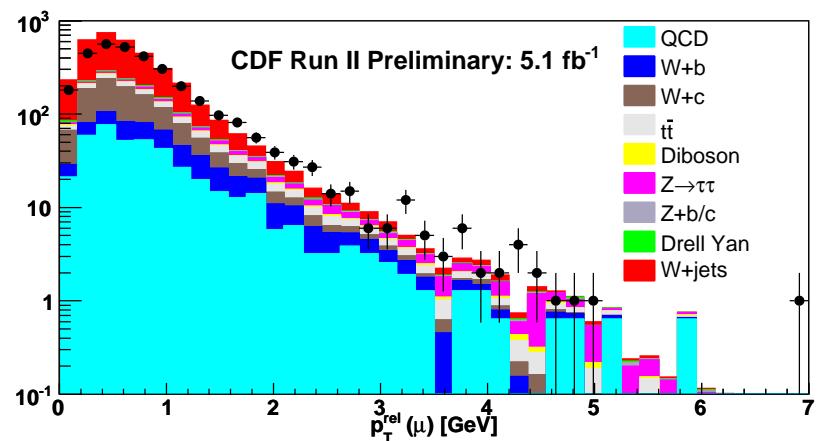
- Use a soft muon tagger originally used for flavor tagging at CDF, ported to our data format
- Uses matching between track and hits in muon detectors, e.g. Δx , Δz , $\Delta\phi$
- $\mathcal{L} = \frac{Q-n}{\sqrt{var(Q)}}$ where Q is a sum of χ^2 's of stub-track matching variables
- Tested on μ from J/ψ , π & K from D^* , and p from Λ .

Soft Muon Efficiency and Fake Rate

- Likelihood tested on μ, π, K, p
- Efficiency and fake rate calculated in bins of p_T and η
- Calculated efficiency and fake rate are applied to the MC to predict SM background
- Systematic uncertainty calculated from difference between expected and observed rate in jet-triggered fake samples

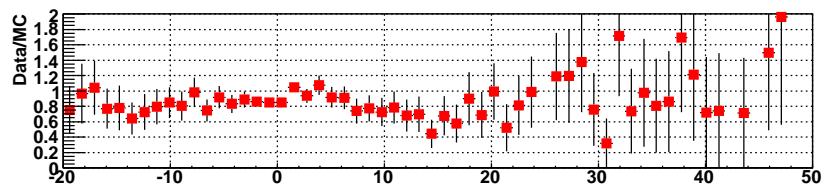
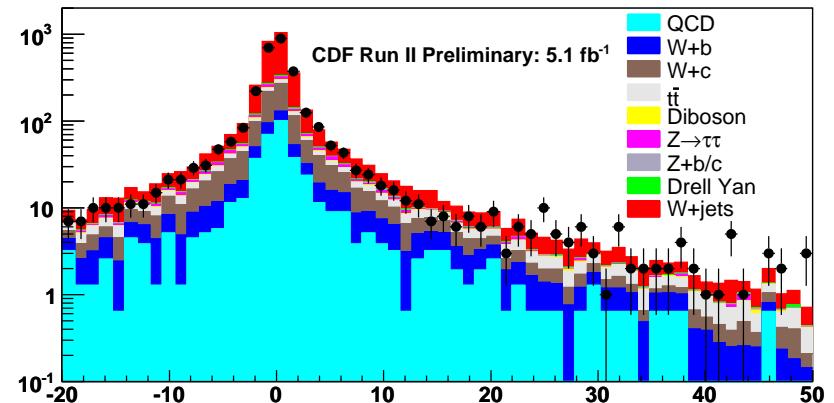
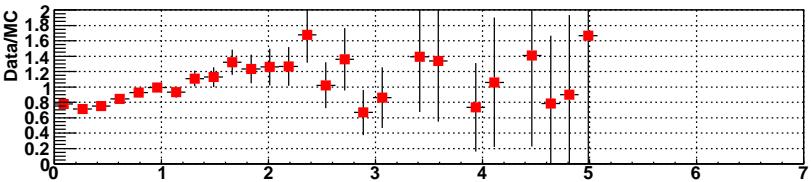
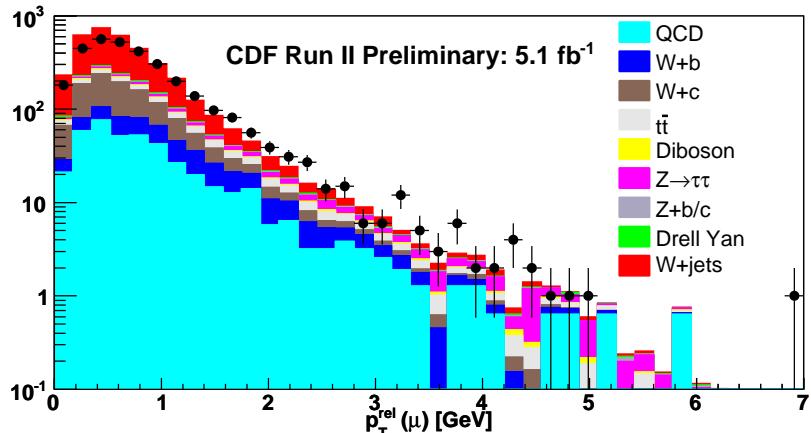


Background Estimation - Heavy Flavor Fraction

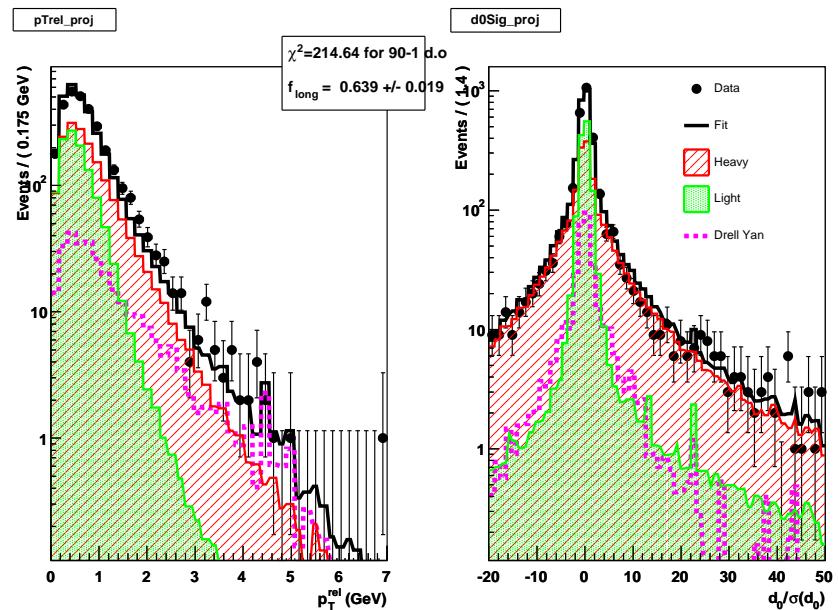


- Semileptonic decays of heavy flavor are the principal background source of real soft leptons
- We find that the amount of heavy flavor is underestimated in our MC after applying the standard scale factors

Background Estimation - Heavy Flavor Fraction



- We fit p_T^{rel} and d_0 of soft muons in the “one additional muon” bin
- We fit to templates from light, heavy, and Drell-Yan processes
- We use the result of this fit as a systematic on heavy flavor fraction



Background Estimation - Normalization

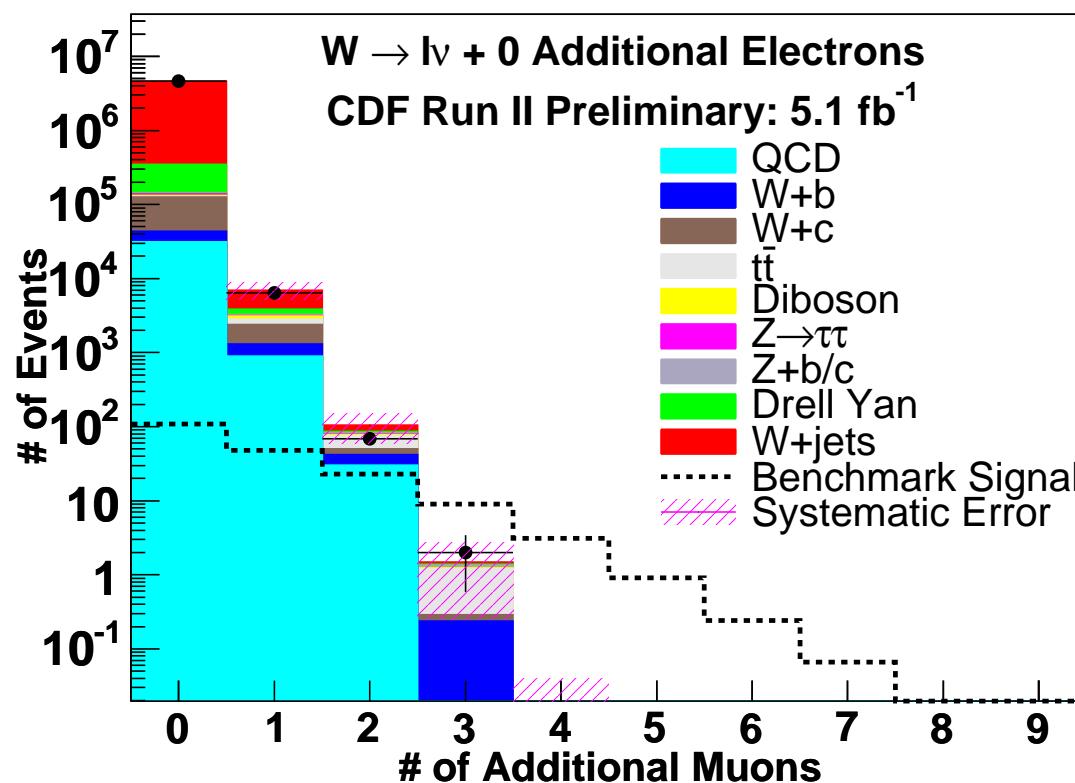
- We scale the background estimate to the one additional lepton bin
 - Expected to be dominated by Standard Model (heavy flavor, Drell-Yan, etc.)
- For events with no additional electrons, we scale to one additional muon
- For events with no additional muons, we scale to one additional electron
- For events with both, we scale to one additional electron (and use the other scale factor as a systematic)

Systematics

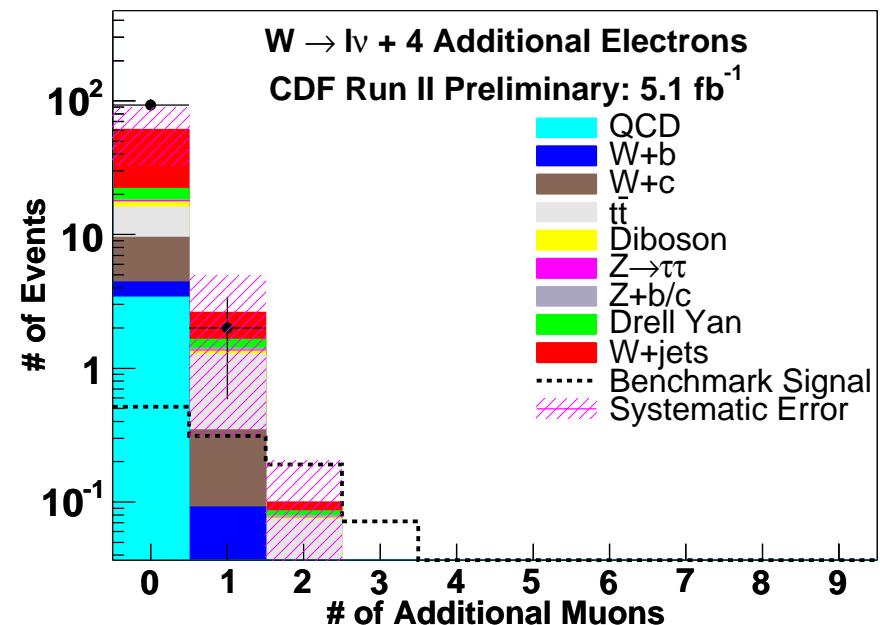
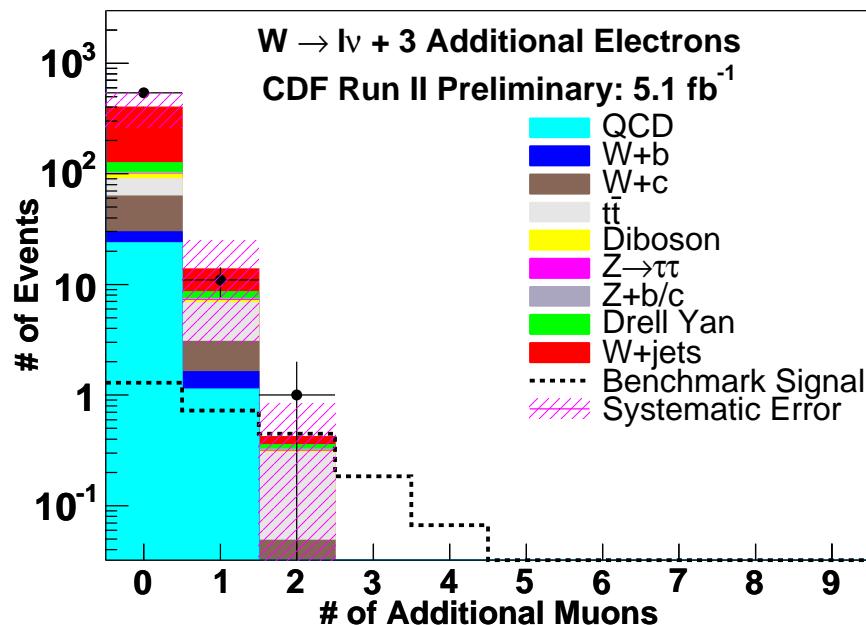
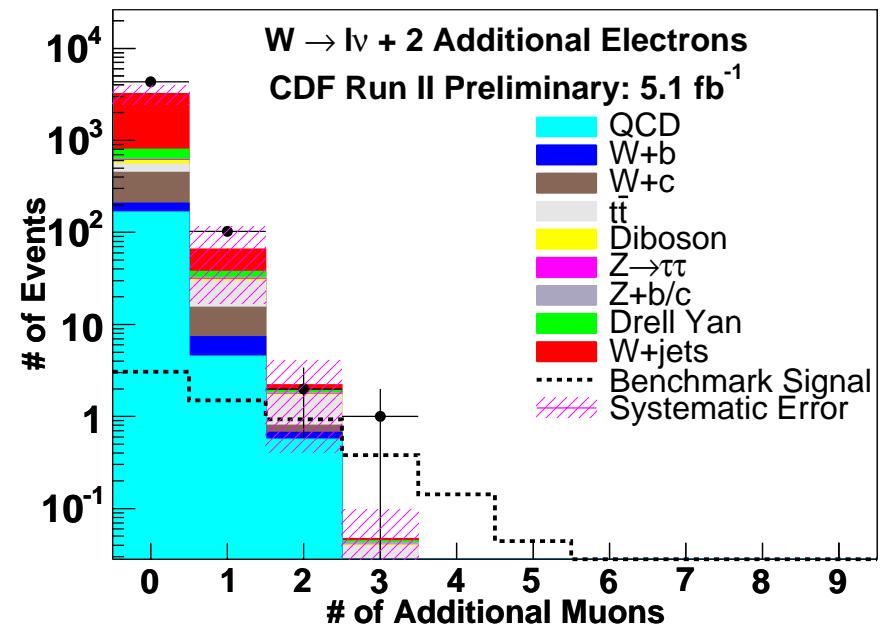
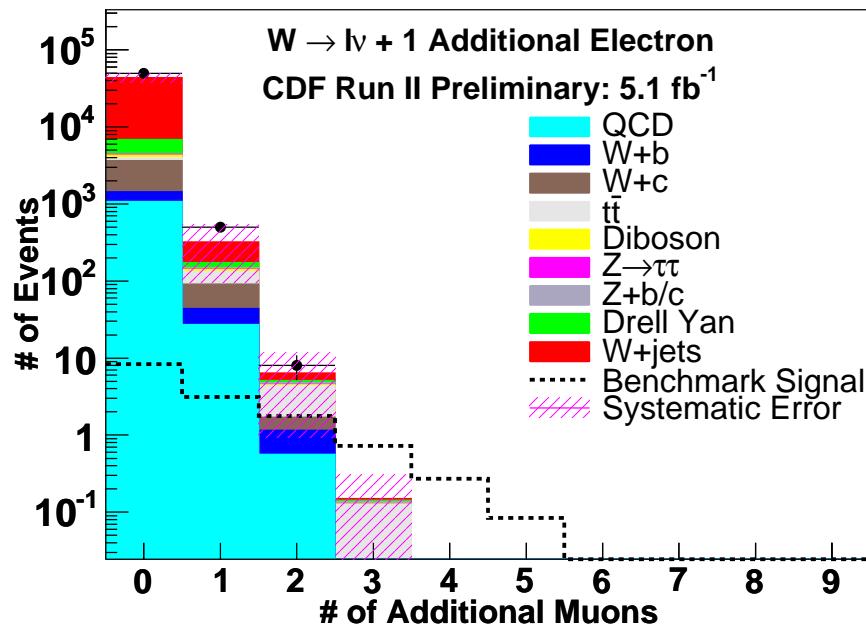
Systematic Source	Uncertainty (Percent)	Effect in Large S/B Region (Events)
Trigger Efficiency	$\pm(1.6 - 5.9)\%$	± 0.06
QCD fraction	$\pm 26\%$	0
Soft e real rate	$\pm 15\%$	± 0.04
Soft e fake rate	$\pm 15\%$	± 0.11
Soft μ real rate	\pm stat. err. $\pm 8\%$	± 0.64
Soft μ fake rate	$\pm 10\%$	± 0.34
Normalization to e or μ	$\pm 48\%$ (W), $\pm 62\%$ (Z)	± 0.12
Heavy Flavor Fraction	$+84\%$ (W), $+225\%$ (Z)	$+1.51$

Results - W

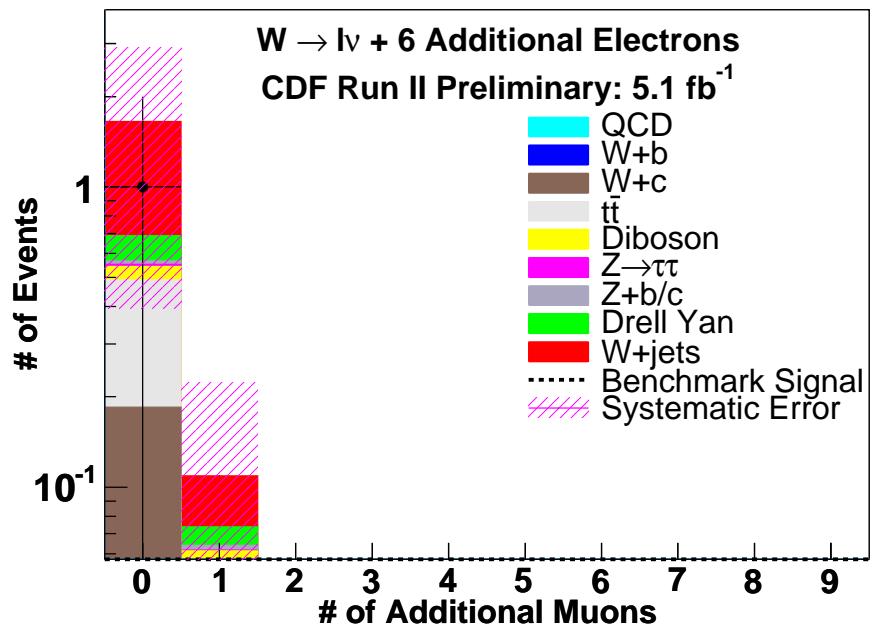
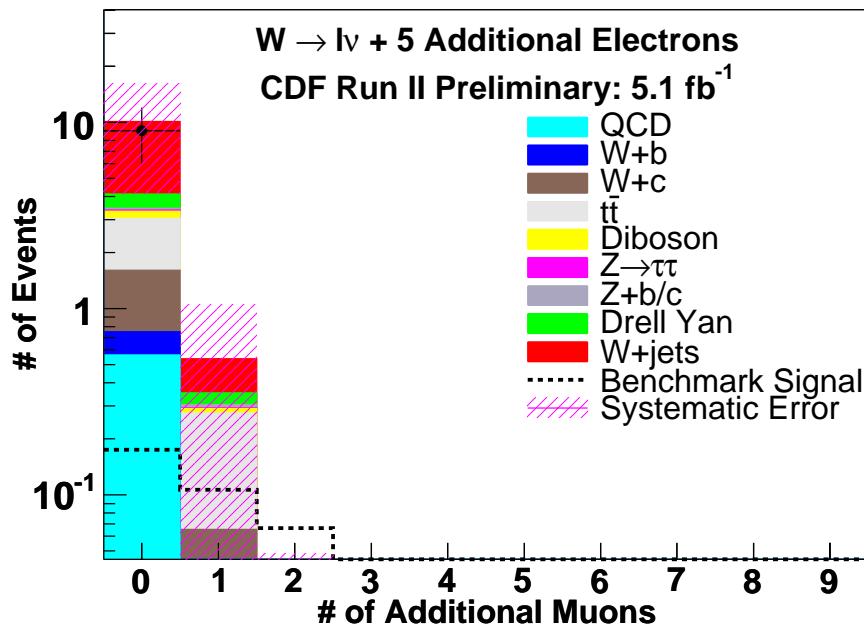
- 2D plot of N_μ vs. N_e , presented in slices of N_e
- Most sensitive in muons, due to photon conversion background



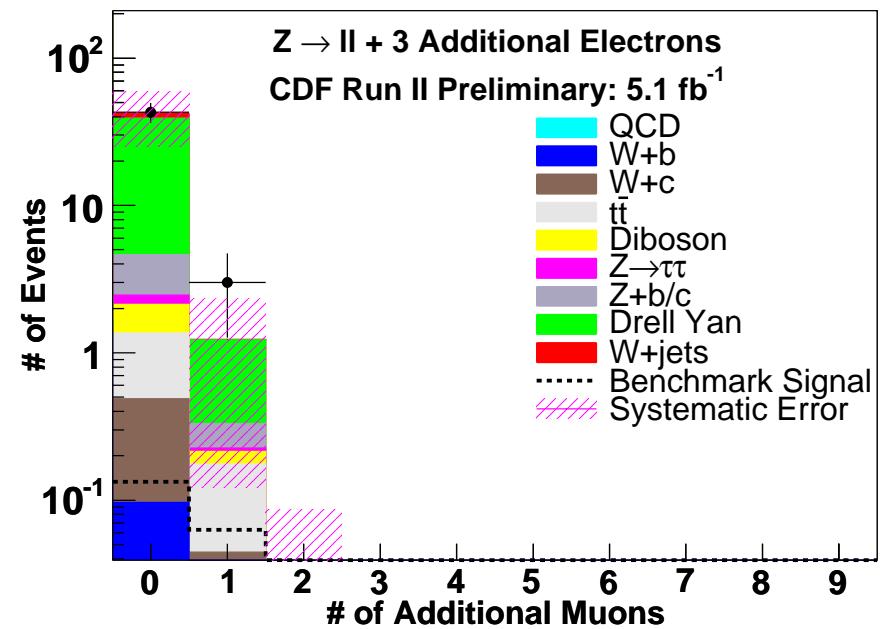
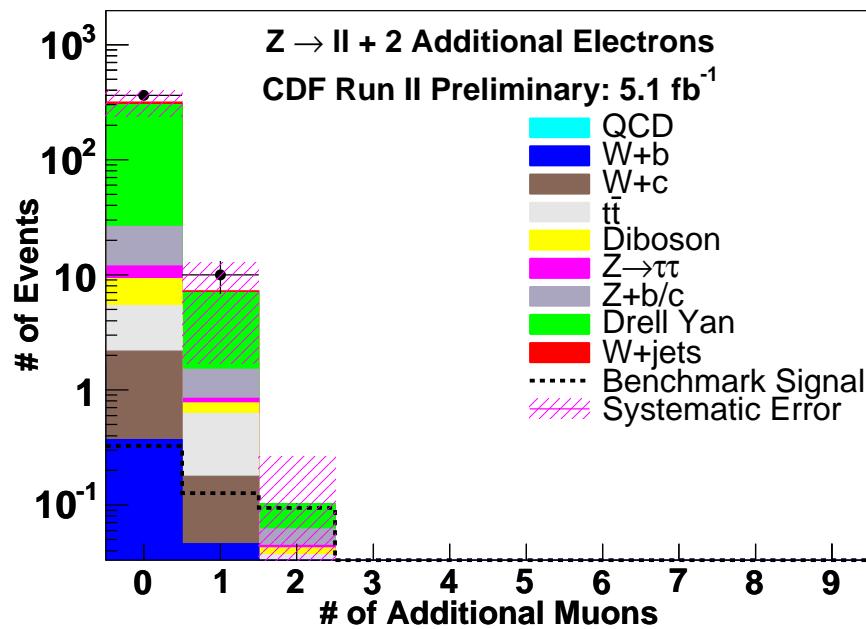
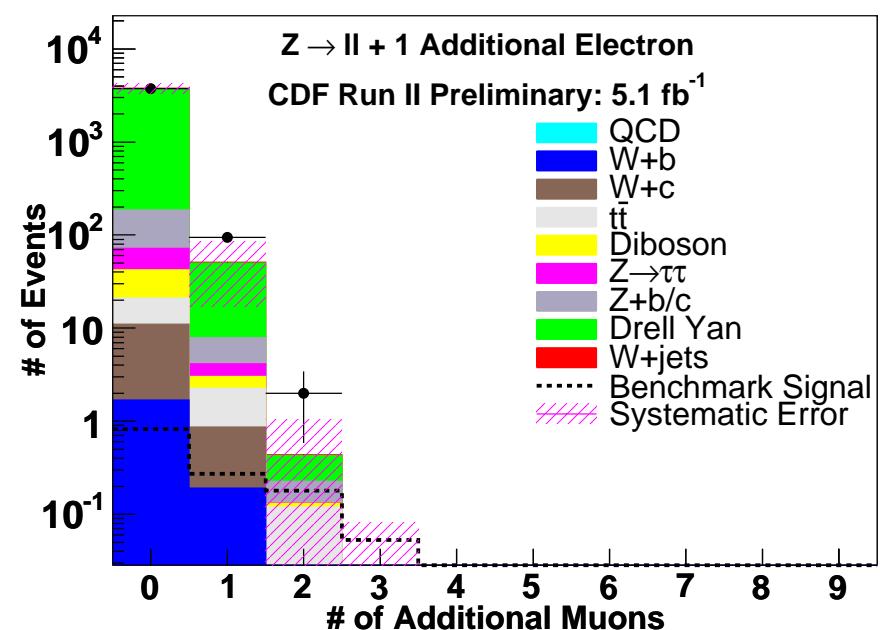
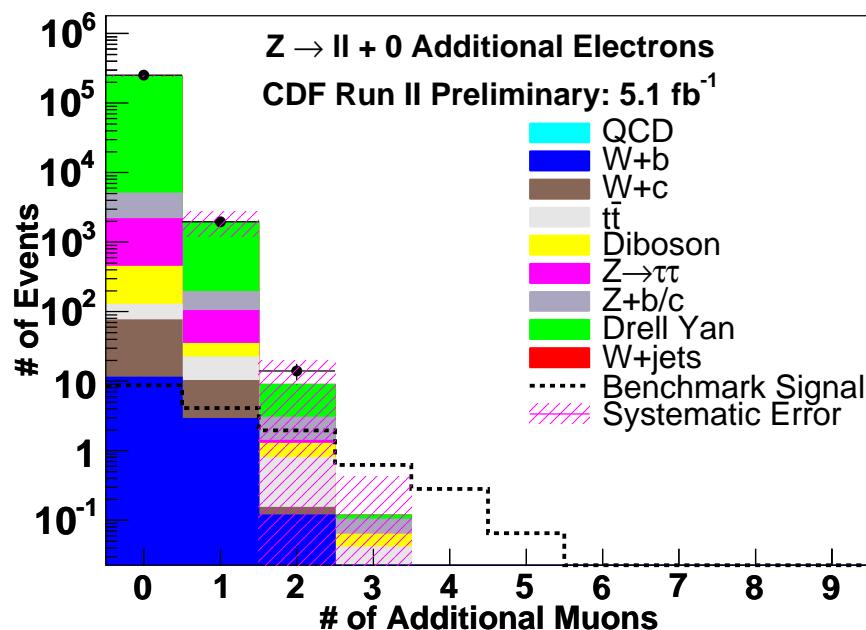
Results - W



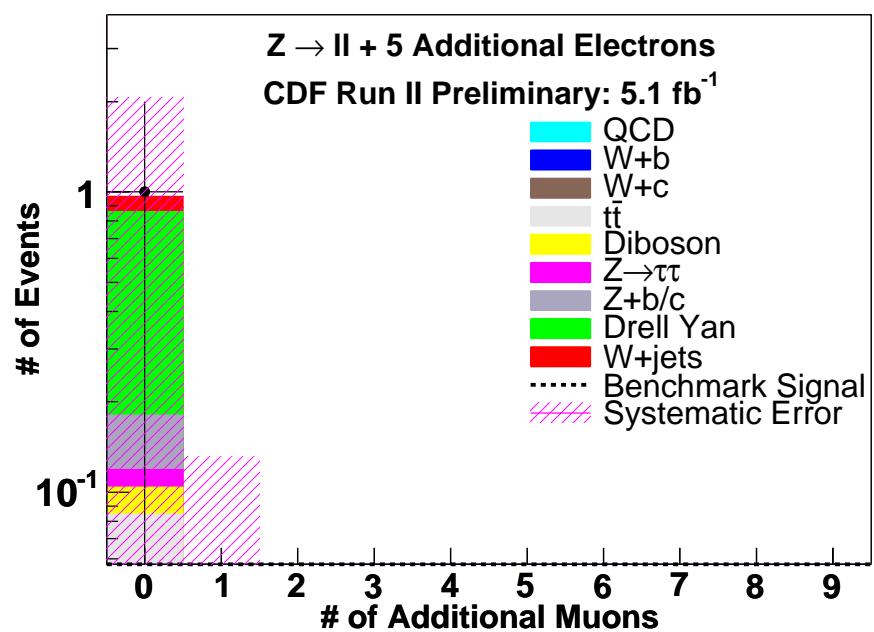
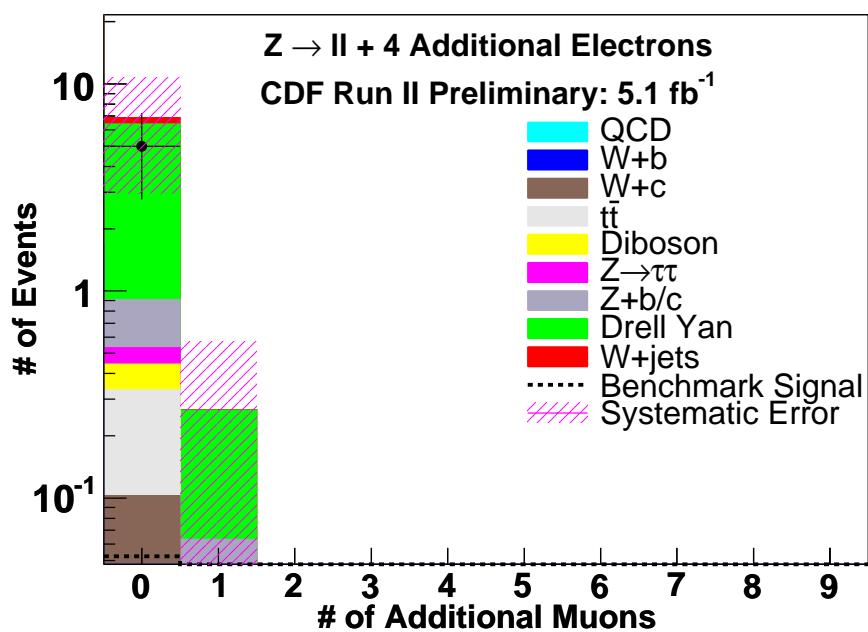
Results - W



Results - Z



Results - Z

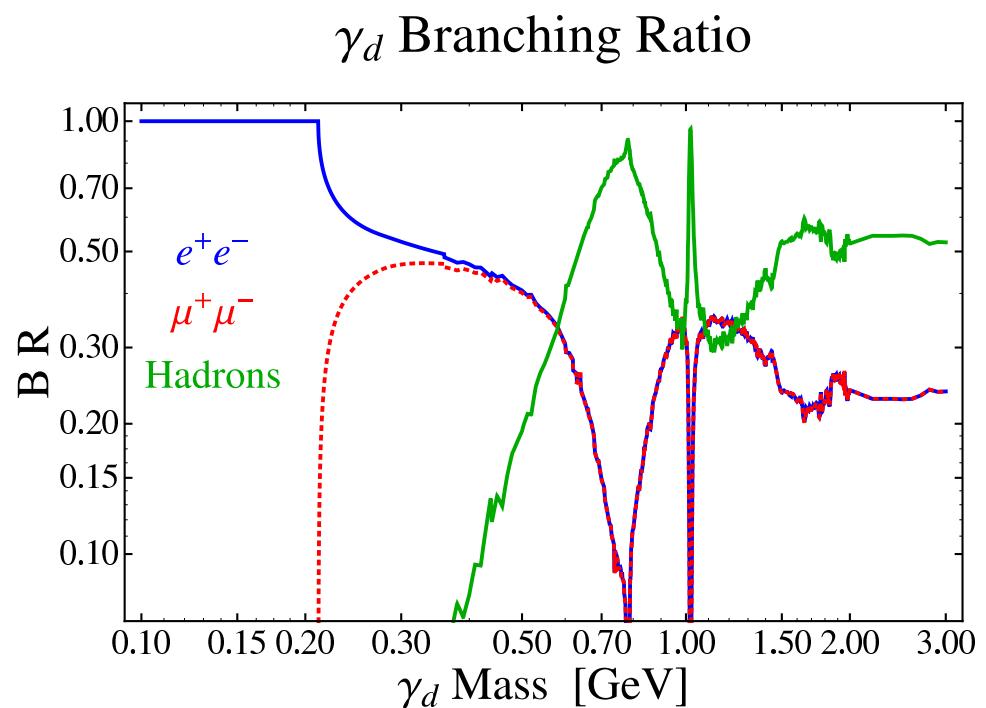


Setting a Limit

- We use the `mclimit` code (T. Junk, NIM A434, p. 435-443 (1999)) to set a limit on our benchmark model
- We rule out the benchmark model at 99.7% confidence.
- We set a 95% confidence level limit on this model of 6.9% of the cross section, or 27 fb for a leptonic W or Z plus a Higgs.

Conclusion

- We rule out this model of a hidden Higgs decaying to a dark sector at 99.7% confidence.
- This is one representative point in this class of models
- We will publish the results in terms of efficiencies to find extra leptons, so that any model can be tested.
- In general, good limits on muon excess, weak limits on electron excess



Results Summary - W

Bins with < 0.25 events expected in BG and signal, and none observed, are not shown.

N_e	N_μ	Predicted SM Background	Predicted Dark Higgs Signal	Observed
0	0	4632580 ± 21334	108	4660910
0	1	6999 ± 1831	48	6402
0	2	106 ± 45	23	69
0	3	1.5 ± 1.2	9.0	2
0	4	0.019 ± 0.020	3.1	0
0	5	0.00018 ± 0.00021	0.92	0
1	0	43551 ± 5403	8.3	49420
1	1	323 ± 227	3.1	498
1	2	6.4 ± 5.5	1.8	8
1	3	0.15 ± 0.16	0.72	0
1	4	0.0025 ± 0.0031	0.27	0

Results Summary - W (continued)

N_e	N_μ	Predicted SM Background	Predicted Dark Higgs Signal	Observed
2	0	3237 ± 763	3.1	4310
2	1	66 ± 49	1.5	103
2	2	2.2 ± 1.8	0.93	2
2	3	0.047 ± 0.051	0.38	1
3	0	402 ± 139	1.3	538
3	1	14 ± 11	0.72	11
3	2	0.42 ± 0.41	0.45	1
4	0	61 ± 28	0.51	93
4	1	2.6 ± 2.3	0.31	2
5	0	10 ± 6.0	0.17	9
5	1	0.54 ± 0.52	0.11	0

Results Summary - Z

N_e	N_μ	Predicted SM Background	Predicted Dark Higgs Signal	Observed
0	0	244858 ± 3263	8.8	252132
0	1	1964 ± 783	4.1	1976
0	2	9.0 ± 11	2.0	14
0	3	0.12 ± 0.30	0.63	0
0	4	0 ± 0.00094	0.28	0
1	0	3797 ± 495	0.82	3747
1	1	51 ± 34	0.27	94
1	2	0.43 ± 0.61	0.18	2
2	0	318 ± 79	0.33	363
2	1	7.2 ± 5.5	0.13	10
3	0	42 ± 17	0.13	43
3	1	1.2 ± 1.1	0.063	3
4	0	6.9 ± 3.9	0.052	5
4	1	0.27 ± 0.30	0.019	0
5	0	0.97 ± 1.1	0.017	1